

## **Carbon nanocrystal-based organic thin-film transistors for nonvolatile memory nanodevices**

### **Abstract**

Organic semiconductor nonvolatile memory devices were successfully fabricated from organic thin-film transistors (OTFTs) embedded with nanocrystal carbon (nc-C) dots incorporating pentacene as an active layer. The nc-C dots were arranged in the channel region by a focused ion beam (FIB) technique using a precursor of low energy Ga<sup>+</sup> ions and a carbon source. The formation and morphology of nc-C dot arrays were investigated using a scanning ion microscopy (SIM) and atomic force microscopy (AFM), respectively. The SIM and AFM images show that the nc-C dot array was successfully grown on the SiO<sub>2</sub> layer. The density of the two-dimensional nc-C dots was  $5 \times 10^9$  cm<sup>-2</sup>. The current-voltage (I - V) characteristics at room temperature show that the fabricated OTFTs exhibit a memory effect upon the application of forward and reverse bias. Under the effect of gate bias, on and off states were induced and a threshold voltage shift ( $\Delta V_{th} = 0.23$  V) was obtained. The charge carrier mobility ( $\mu$ ) of the OTFTs is similar in both on and off states. The memory effect was attributed to the nc-C dots in the pentacene-dielectric interface. © 2009 The Surface Science Society of Japan.